

Search Notes

Application/Control No.

10/623,556

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

SHIRAISHI, KENJI

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	223.1	12/28/2006	NT
348	240.2	12/28/2006	NT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPUB text search - see search history printout		4/6/2007	NT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	12/28/2006	NT
348/223.1-225.1 (text search - see search history printout)	12/28/2006	NT
348/240.1-240.99 (text search - see search history printout)	12/28/2006	NT
Text search all databases listed above	4/6/2007	NT
Inventorship search - see search history printout	4/6/2007	NT